

10/087060  
02/27/02  
APPL NO.

PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10087060	02/27/2002	250		2878	<i>[Signature]</i>

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\*\*CONTINUING DATA VERIFIED:

\*\* FOREIGN APPLICATIONS VERIFIED:

JAPAN P2000-207311 07/07/2000

PCT/JP01/05921 07/06/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	ATTORNEY DOCKET NO
Foreign priority claimed 35 USC 119 conditions met Verified and Acknowledged Examiners initials		<input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> yes <input type="checkbox"/> no	21778.05600
TITLE : Quantity-of-light unevenness inspection apparatus, and quantity-of-light unevenness inspection method			
U.S. DEPT. OF COMM./PAT. & TM-PTO-438L (Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G
ISSUE FEE		DRAWING		
Amount Due	Date Paid	Sheets Drwg.	Figs.Drwg.	Print Fig.
TERMINAL		Primary Examiner		
DISCLAIMER		PREPARED FOR ISSUE		
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